Enhanced photovoltaic output of bifacial perovskite solar cells via tailoring photoelectric balance in rear window layers with 1T-WS<sub>2</sub> nanosheets engineering

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Fig. S1 Top-view molecule structures of 1T-WS<sub>2</sub>. W atoms are in green and S atoms are in purple and blue for top and bottom layers, respectively.



Fig. S2 HRTEM image of spiro-OMeTAD film.

Fig. S3 (a) Raman spectra of SP and SP + W films. (b) Surface SEM image and elemental mappings (W and S) of SP + W film.



**Fig. S4** UV–vis absorption spectra of SP and SP + W films.

**Fig. S5** (a) TRPL plots and fitting curves of Glass/PVK/SP and Glass/PVK/SP + W substrates. (b) Nyquist plots of solar cells based on SP and SP + W HTLs, obtained with a bias of 0.8 V in dark. Inset: equivalent circuit used to fit the data.

Fig. S6 (a) OCVD curves and (b) dark-current measurements of the corresponding devices.

**Fig. S7** Optimization of the optical and electrical properties of different SP + W films deposited on ITO-glass substrates: (a) transmittance, (b) UV-vis absorption, and (c) conductivity.

Fig. S8 (a) J-V curves of the best-performing SP-based b-PSC illuminated on different sides. (b) Corresponding EQE spectra and integrated  $J_{SC}$ . **Fig. S9** Steady-state current densities measured at the voltage of the maximum power point for (a) SP and (b) SP + W b-PSCs.

Table S1 Hall measurement results of SP and SP + W films

	(S/cm)	(Ω·cm)	(cm <sup>2</sup> /V·s)	(nm)
SP	5.00×10 <sup>-7</sup>	$2.00 \times 10^{6}$	3.57×10 <sup>-3</sup>	~ 230 nm
SP + W	6.57×10 <sup>-5</sup>	$1.50 \times 10^{4}$	6.04×10 <sup>-3</sup>	~ 150 nm

Samples	$R_{\rm s}(\Omega)$	$R_{ m tr}(\Omega)$	$R_{ m rec}(\Omega)$	$C_{\rm tr}({\rm F})$	$C_{\rm rec}({ m F})$
SP	34.21	24.66	383.3	7.3×10 <sup>-9</sup>	5.6×10-9
SP + W	27.86	18.81	468.3	7.1×10-9	6.4×10 <sup>-9</sup>

**Experimental section** 

## Materials and reagents:

Etched indium-doped tin oxide (ITO, 2 × 2 cm<sup>2</sup>) conducting glasses were purchased from Yingkou Optimum Trade Co., Ltd., whereas tin oxide colloidal dispersion (SnO<sub>2</sub> 15% in H<sub>2</sub>O colloidal dispersion), dimethyl sulfoxide (DMSO,  $\geq$ 99.8%), N,N-dimethylformamide (DMF,  $\geq$  99.8%), and methylammonium iodide (CH<sub>3</sub>NH<sub>3</sub>I, MAI,  $\geq$  99.8%) were purchased from Alfa Aesar. Lead (II) iodide (PbI<sub>2</sub>,  $\geq$ 99.999%) and chlorobenzene (CB,  $\geq$  99.5%) were obtained from Sigma-Aldrich and Aladdin Reagent, respectively. Tungsten disulfide nanosheet powder (WS<sub>2</sub>, average lateral size: ~ 100 nm) was purchased from Nanjing XFNANO Materials Co., Ltd. The 2,2',7,7'-tetrakis [N,N-di(4-meth-oxyphenyl)amino]-9,9'-spirobifluorene (spiro-OMeTAD,  $\geq$  99.0%), sulfonyl imide (Li-TFSI,  $\geq$  99%), acetonitrile ( $\geq$  99.9%), and 4tertbutylpyridine (TBP,  $\geq$  99%) were supplied by Yingkou Optimum Trade Co., Ltd. The purity of the silver (Ag) used for thermally evaporated electrode was 99.99%. All chemicals and reagents were directly used without further purification.

## Materials and devices characterization:

Transmission electron microscopy (TEM) images were taken using a JEOL-2010 TEM operating at a 200 kV accelerating voltage. The surface and cross-sectional morphologies of samples were measured using a field-emission scanning electron microscopy (SEM, JEOL, JSM-7800F). The material states of samples were characterized by means of Raman spectroscopy (Nanofinder 30, Tokyo Instruments Inc.), using laser excitation with a 514 nm wavelength. The optical properties, including transmission and absorption, were recorded on an UV-vis spectrophotometer (SHTMADZU, UV-3600plus). The relevant electrical parameters of different films were analyzed by a four-point probe system with a current sourcemeter (RS8, BEGA Technologies). X-ray photoelectron spectroscopy (XPS) and ultraviolet photoelectron spectroscopy (UPS) were performed using an XPS/UPS system (Thermofisher, Excalab 250 xi). The chemical composition and state analysis of samples were measured by XPS, and the energy band structure was evaluated by UPS with the He I (21.22 eV) emission line employed for excitation. The surface potentials of films were measured with Kelvin probe force microscope (KPFM, Park Systems NX20, Korea). The time-resolved photoluminescence (TRPL) spectrum was measured by a Fluorolog-3-TCSPC spectrometer (Edinburgh Instruments, FLS1000, UK). The electrochemical impedance spectroscopy (EIS) of solar cells was performed using an electrochemical workstation (CHI660C) at a voltage bias of 0.8 V in dark. The photocurrent density-voltage (J-V) curves of solar cells with different incident light directions were acquired using a solar simulator (Newport Oriel Solar 3A Class AAA) equipped with a 150-W xenon lamp under AM 1.5G (100 mW/cm<sup>2</sup>) simulated sunlight. Light intensity was calibrated using a standard KG3-filtered silicon reference cell certified by the National Renewable Energy Laboratory. All devices were reverse scanned (from 1.2 V to -0.2 V) at a scan rate of 130 mV/s, and the active area was delimited using the metal mask. The spectral response of devices was taken by an external quantum efficiency (EQE) measurement system (Newport, IQE 200<sup>TM</sup>), equipped with a monochromator, a lock-in amplifier, a Xe lamp, and a current-voltage amplifier.